Notice of References Cited	Application/Control No. 10/574,219	Applicant(s)/Patent Under Reexamination SCHULZ ET AL.	
Notice of References offed	Examiner Art Unit		
	LUKE E. KARPINSKI	1616	Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,294,330 B2	11-2007	Banowski et al.	424/65
	В	US-			
	U	US-			
	ם	US-			
	ш	US-			
	F	US-			
	O	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	WO03039505A3	05-2003	WIPO	Banowski	
	0					
	Ρ					
	Ø					
	R					
	Ø					
·	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.